



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Kim, et al.

Serial No.: 10/732,904

Confirmation No.: Unassigned

Filed:

December 10, 2003

For:

Nitrogen-Free Dielectric Anti-

Reflective Coating and Hardmask

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Group Art Unit: Unassigned

Examiner:

Unassigned

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

CERTIFICATE OF MAILING 37 CFR 1.8

I hereby certify that this correspondence is being deposited on February ______, 2004, with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.

2/18/04

Signature

INFORMATION DISCLOSURE STATEMENT

The Applicants, and the Attorney who signs below on the basis of the information supplied by the inventor and the information in his file, submit herewith patents, publications, or other information of which they are aware, which may be material to the examination of this application and in respect of which there may be a duty to disclose in accordance with 37 CFR § 1.56.

While the information submitted in this Information Disclosure Statement may be material pursuant to 37 CFR § 1.56, it is not intended to constitute an admission that any patent, publication, or other information referred to therein is prior art for this invention unless specifically designated as such.

In accordance with 37 CFR § 1.97, this Information Disclosure Statement is not to be construed as a representation that a search has been made or that no other possibly material information as defined under 37 CFR § 1.56(a) exists.

The patents and/or publications submitted herewith are set forth on the attached Form PTO-1449.

If the sum of \$180.00 is due under 37 CFR § 1.17(p) pursuant to § 1.97, the Commissioner is hereby authorized to charge this fee, and any other fee necessary to make this submission timely, to the Deposit Account No. 20-0782/AMAT/6826.P1/KMT.

Respectfully submitted,

Keith M. Tackett

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Houston, TX 77056

Telephone: (713) 623-4844 Facsimile: (713) 623-4846 Attorney for Applicant(s) Please type a plus on (+) inside this box -> +

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or form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1 of 12

Application Number	10/732,904
Filing Date	December 10, 2003
First Named Inventor	Kim, et al.
Group Art Unit	Unassigned
Examiner Name	Unassigned
Attorney Docket Number	AMAT/6826.P1/DSM/BCVD/JW
Submission Date	February <u>/</u> \$_, 2004

			U.S. PATENT	DOCUMENTS	
Examiner Cite Initials* No.1		Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant
	<u> </u>	Number-Kind Code ^{2 (if known)}			Figures Appear
	A1	US-6,596,465	07/22/2003	Mangat, et al.	
	A2	US-6,573,030	06/03/2003	Fairbairn, et al.	
	А3	US-6,541,397B1	04/01/2003	Bencher	
	A4	US-6,514,667	02/04/03	Angelopoulos, et al.	
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	A9	US-6,492,731	12/10/02	Catabay, et al.	
	A10	US-6,489,233	12/03/02	Chooi, et al.	
	A11	US-6,485,815	11/26/02	Jeong, et al.	
	A12	US-6,482,754	11/19/02	Andideh, et al.	
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Examiner	Cite	Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines,	Τ ⁶				
Initials*	No.¹	Number-Kind Code ^{2 (if known)}	MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear					
	B1	02/43119	05/30/02	wo						
	B2	01/01472	01/04/01	wo						
	В3	00/24050	04/27/00	wo						
	B4	00/19498	04/06/00	wo						
	B5	00/01012	01/06/00	wo						

Examiner Date Considered

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10/732,904 Substitute for form 1449A/PTO **Application Number** Filing Date December 10, 2003 INFORMATION DISCLOSURE First Named Inventor Kim, et al. STATEMENT BY APPLICANT **Group Art Unit** Unassigned **Examiner Name** Unassigned (Use as many sheets as necessary) Attorney Docket Number AMAT/6826.P1/DSM/BCVD/JW Sheet 12 Submission Date February **/8** ,2004

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Examiner Cite Initials* No.1		Document Number	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where					
Initials*	No.	Number-Kind Code ^{2 (if known)}	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear					
	A1	US-6,472,231	10/29/02	Gabriel, et al.						
	A2	US-6,462,371	10/08/02	Weimer, et al.						
	A3	US-6,458,720	10/01/02	Aoi						
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	A18	US-6,348,725	02/19/02	Cheung, et al.						

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	B1	99/55526	11/04/99	wo	***					
	B2	99/33102	07/01/1999	wo						
	В3	99/41423	08/19/99	wo						
	B4	99/38202	07/29/99	wo						
	B5	98/59089	12/30/98	wo		_				

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initials*	No.	Number-Kind Code ^{2 (if known)}	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear				
	A1	US-6,348,421	02/19/02	Shu, et al.					
	A2	US-6,346,747	02/12/02	Grill, et al.					
	A3	US-6,340,628	01/22/02	Van Cleemput, et al.					
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Initials*	No.¹	Number-Kind Code ^{2 (if known)}	MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear					
	B1	98/08249	02/26/98	wo						
	B2	11-251293	09/17/99	JP						
	В3	10-242143	09/11/98	JP						
	B4	09-260369	10/03/97	JP						
	B5	09-251997	09/22/97	JP						

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Substitute	e for form 1449A/PTO			Application Number	10/732,904
				Filing Date	December 10, 2003
INFO	RMATION DISC	CLO	SURE	First Named Inventor	Kim, et al.
STAT	TEMENT BY AP	PLIC	CANT	Group Art Unit	Unassigned
				Examiner Name	Unassigned
	(Use as many sheets as necessary)			Attorney Docket Number	AMAT/6826.P1/DSM/BCVD/JW
Sheet	4	of	12	Submission Date	February 18, 2004

			U.S. PATENT	DOCUMENTS	
Examiner	Cite	Document Number	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where
Initials*	No. ¹	Number-Kind Code ^{2 (if known)}	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear
	A1	US-6,093,973	07/25/00	Ngo, et al.	
	A2	US-6,080,526	06/27/00	Yang, et al.	
	А3	US-6,078,133	06/20/00	Menu, et al.	
	A4	US-6,072,227	06/06/00	Yau, et al.	
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	A7	US-6,048,786	04/11/00	Kudo	
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Examiner	Cite	Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines,	T ⁶				
Initials*	No. ¹	Number-Kind Code ^{2 (if known)}	MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear					
	B1	09-237785	09/09/97	JP						
	B2	09-064029	03/07/97	JP						
	В3	09-008031	01/10/97	JP		-				
	B4	01-125193	05/17/89	JP		_				
	B5	2000306999 (abstract)	11-02/00	JP						

Examiner Date Considered

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				Filing Date	December 10, 2003
INFO	RMATION DISC	LOS	SURE	First Named Inventor	Kim, et al.
STAT	TEMENT BY AP	PLI(CANT	Group Art Unit	Unassigned
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Sheet	5	of	12	Submission Date	February <u>/8</u> , 2004

U.S. PATENT DOCUMENTS								
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Initials*	No.	Number-Kind Code ^{2 (if known)}	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear			
	A1	US-5,874,367	02/23/99	Dobson				
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	A3	US-5,837,331	11/17/98	Menu, et al.				
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Initials*	No.¹	Number-Kind Code ^{2 (if known)}	MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear				
	B1	2 316 535	02/25/98	GB					
	B2	1 176 226 A1	01/30/02	EP					
	В3	1 123 991 A2	08/16/01	EP					
	B4	1 037 275 A1	09/20/00	EP	,				
	B5	0 935 283 A2	08/11/99	EP					

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				Filing Date	December 10, 2003	
INFO	RMATION DISC	CLO	SURE	First Named Inventor	Kim, et al.	
STAT	TEMENT BY AF	PLIC	CANT	Group Art Unit	Unassigned	
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(Use as many sheets as necessary))	Attorney Docket Number	AMAT/6826.P1/DSM/BCVD/JW	
Sheet	6	of	12	Submission Date	February 18 2004	

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Initials*	No. ¹	Number-Kind Code ^{2 (if known)}	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear	
	A1	US-5,693,563	12/02/97	Teong		
	A2	US-5,683,940	11/04/97	Yahiro		
	A3	US-5,679,413	10/21/97	Petrmichl, et al.		
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-	A5	US-5,674,355	10/07/97	Cohen, et al.		
	A6	US-5,641,607	06/24/97	Ogawa, et al.		
	A7	US-5,638,251	06/10/97	Goel, et al.		
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	A9	US-5,618,619	04/08/97	Petrmichl, et al.		
	A10	US-5,616,369	04/01/97	Williams, et al.		
	A11	US-5,599,740	02/04/97	Jang, et al.		
	A12	US-5,598,027	01/28/97	Matsuura		
	A13	US-5,593,741	01/14/97	Ikeda		
	A14	US-5,591,566	01/07/97	Ogawa		
	A15	US-5,559,367	09/24/96	Cohen, et al.		
	A16	US-5,494,712	02/27/96	Hu, et al.		
	A17	US-5,360,491	11/01/94	Carey, et al.		
	A18	US-5,298,587	03/29/94	Hu, et al.		

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	B5	0 926 724 A2	06/30/99	EP					
	B1	0 926 715 A2	06/30/99	EP					
	B2	0 960 958 A2	12/01/99	EP					
	В3	0 935 283 A2	08/11/99	EP					
	B4	0 885 983 A1	12/23/98	EP					

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	A1	US-5,186,718	02/16/93	Tepman, et al.		
	A2	US-4,486,286	12/04/84	Lewin, et al.		
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Substitut	e for form 1449A/PTO			Application Number	10/732,904
				Filing Date	December 10, 2003
INFO	PRMATION DISC	CLOS	SURE	First Named Inventor	Kim, et al.
STA	TEMENT BY AP	PLI(CANT	Group Art Unit	Unassigned
				Examiner Name	Unassigned
	(Use as many sheets as neo	cessary,)	Attorney Docket Number	AMAT/6826.P1/DSM/BCVD/JW
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Substitute	for form 1449B/PTO			Application Number	10/732,904
				Filing Date	December 10, 2003
INFO	RMATION DISC	CLOS	SURE	First Named Inventor	Kim, et al.
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				Examiner Name	Unassigned
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Substitute for form 1449B/PTO				Application Number	10/732,904
				Filing Date	December 10, 2003
INFO	RMATION DISC	CLOS	SURE	First Named Inventor	Kim, et al.
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				Examiner Name	Unassigned
1	(Use as many sheets as ne	cessary,	•	Attorney Docket Number	AMAT/6826.P1/DSM/BCVD/JW
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	Substitute	for form 1449B/PTO			Application Number	10/732,904
					Filing Date	December 10, 2003
	INFO	RMATION DISC	CLOS	SURE	First Named Inventor	Kim, et al.
	STAT	TEMENT BY AP	PLIC	CANT	Group Art Unit	Unassigned
					Examiner Name	Unassigned
		(Use as many sheets as ne	cessary)	Attorney Docket Number	AMAT/6826.P1/DSM/BCVD/JW
	Sheet	11	of	12	Submission Date	February 1g , 2004

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Substitute	for form 1449B/PTO			Application Number	10/732,904
				Filing Date	December 10, 2003
INFO	RMATION DI	SCLOS	SURE	First Named Inventor	Kim, et al.
STAT	EMENT BY	APPLI(CANT	Group Art Unit	Unassigned
				Examiner Name	Unassigned
	(Use as many sheets as	s necessary)		Attorney Docket Number	AMAT/6826.P1/DSM/BCVD/JW
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